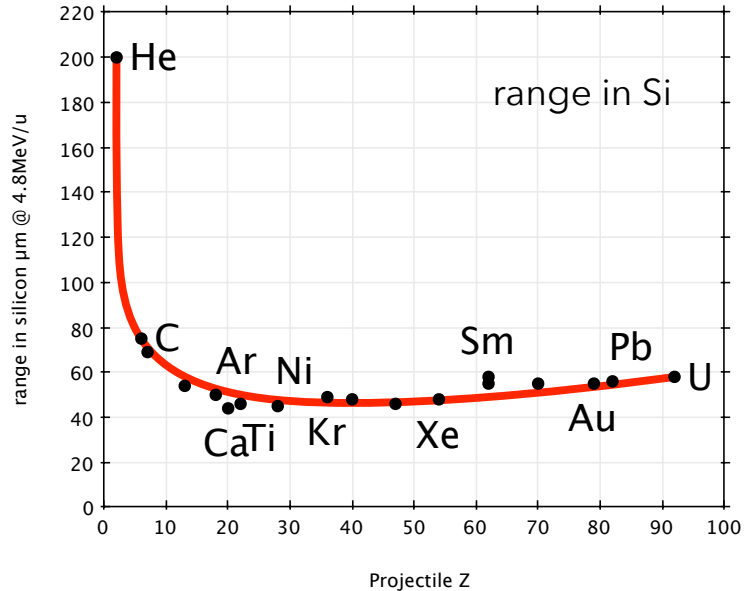
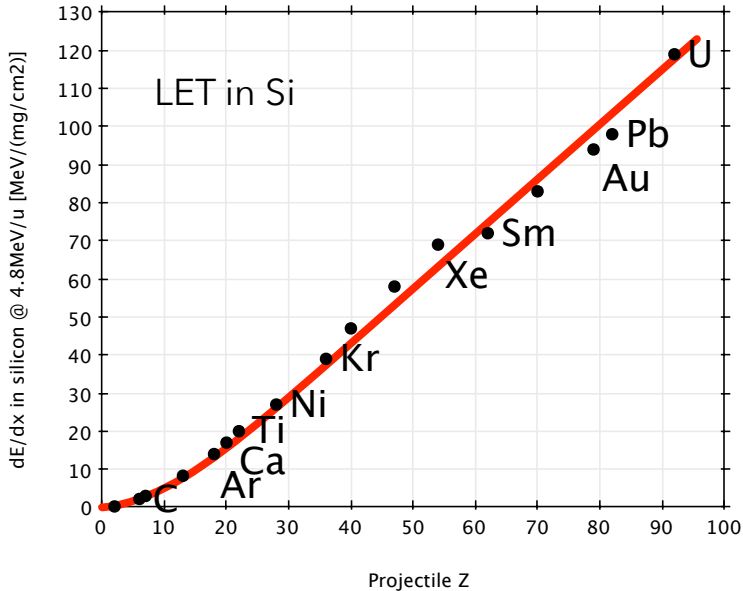


# Electronics Testing Fact Sheet 'Microprobe'

## LETs and ranges in Silicon at standard 4.8MeV/u\*



### Single-Event-Effect Testing with Spatial Resolution

The beam spot is scanned across the target surface. For each impacting ion the SEE is recorded along with the corresponding impact position. A 2D map of SEE is created.

- ▶ resolution 500nm
- ▶ max. flux 20Hz to 2kHz
- ▶ scan area max. 0.5x0.5 mm<sup>2</sup>
- ▶ perfect dosimetry
  
- ▶ CAMAC data acquisition
- ▶ optical microscopy for beam positioning
- ▶ interface to/from user equipment
- ▶ cooled sample stage in vacuum
- ▶ rack space at target chamber
- ▶ target chamber space for support electronics

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\*up to 11.4MeV/u possible: Double range, lower flux, smaller scan area, possibly extra stripping